## Notice of References Cited

Application/Control No. 10/558,436		Applicant(s)/Patent Under Reexamination LEE ET AL.		
Examiner	Art Unit			
CHUONG T. HO	2476	Page 1 of 1		

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2008/0097631	04-2008	Baek et al.	700/90
*	В	US-6,701,198	03-2004	Vandesteeg et al.	700/79
*	С	US-6,721,900	04-2004	Lenner et al.	714/4
*	D	US-6,631,476	10-2003	Vandesteeg et al.	714/4
*	Е	US-6,891,850	05-2005	Vandesteeg et al.	370/466
*	F	US-6,915,444	07-2005	Vasko et al.	714/4
*	G	US-7,107,358	09-2006	Vasko et al.	709/249
*	Н	US-2003/0051053	03-2003	Vasko et al.	709/246
*	Т	US-2006/0271709	11-2006	Vasko et al.	709/249
*	J	US-2003/0051203	03-2003	Vasko et al.	714/781
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q		1			
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

_	NON-FAIENT DOCUMENTS		
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U		
	v		
	w		
	×		

"A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.